

# **Notice of References Cited**

Application/Control No.

10/021,706

Applicant(s)/Patent Under  
Reexamination  
CHIOU ET AL.

Examiner

Brian R. Gordon

Art Unit

1743

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## **U.S. PATENT DOCUMENTS**

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## **NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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